


<b>Search Notes</b>  	<b>Application/Control No.</b>  10540486	<b>Applicant(s)/Patent Under Reexamination</b>  NISHIKOUJI ET AL.
	<b>Examiner</b>  Nguyen, Lauren	<b>Art Unit</b>  2871

SEARCHED			
Class	Subclass	Date	Examiner
349	117-120	02/28/2007	LN

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted Primary Examiner Andrew Schechter	02/28/2007	LN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
349	117, 119	1/20/2009	LN

/L. N./  
Examiner, Art Unit 2871